Power MOSFET

30 V, 104 A, Single N-Channel, SO-8 FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These are Pb-Free Devices

Applications

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	20	Α
Current $R_{\theta JA}$ (Note 1)		T _A = 85°C		14	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	2.27	W
Continuous Drain		T _A = 25°C	I _D	12	Α
Current R _{θJA} (Note 2)	Steady State	T _A = 85°C		9.0	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	T _A = 25°C	P _D	0.89	W
Continuous Drain		T _C = 25°C	I _D	104	Α
Current $R_{\theta JC}$ (Note 1)		T _C = 85°C		75	
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C	P _D	62.5	W
Pulsed Drain Current	T _A = 25°C, t _p = 10 μs		I _{DM}	208	Α
Operating Junction a Temperature	Operating Junction and Storage Temperature			–55 to +150	°C
Source Current (Boo	Source Current (Body Diode)			52	Α
Drain to Source DV/DT			d _V /d _t	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy $T_J=25^{\circ}C$, $V_{DD}=50$ V, $V_{GS}=10$ V, $I_L=28$ A_{pk} , $L=1.0$ mH, $R_G=25$ Ω			E _{AS}	392	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

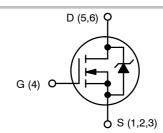
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.



ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	3.5 mΩ @ 10 V	101.4
30 V	5.0 mΩ @ 4.5 V	104 A



N-CHANNEL MOSFET

MARKING DIAGRAM

S

S

S

4835N

AYWW=

D



SO-8 FLAT LEAD CASE 488AA STYLE 1

= Assembly Location

= Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4835NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4835NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.0	
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	55.1	°C/W
Junction-to-Ambient - Steady State (Note)	$R_{\theta JA}$	140.1	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•			•		•	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				22.4		mV/°C
Zero Gate Voltage Drain Current	I _{DSS} V _{GS} = 0 V,		T _J = 25 °C			1.0	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = ±20 V				±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$: 250 μA	1.5	1.9	2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.3		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	11.5 V	I _D = 30 A		2.9	3.5	- mΩ
			I _D = 15 A		2.5		
			I _D = 30 A		4.3	5.0	
			I _D = 15 A		3.9		
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 15 A			21		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE			•	•	•	
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			3100		pF
Output Capacitance	C _{OSS}				670		
Reverse Transfer Capacitance	C _{RSS}				360		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			22	39	nC
Threshold Gate Charge	Q _{G(TH)}				4.7		
Gate-to-Source Charge	Q_{GS}				8.3		
Gate-to-Drain Charge	Q_{GD}				8.8		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 11.5 V, V _{DS} = 15 V; I _D = 30 A			52		nC
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t _{d(ON)}				16		
Rise Time	t _r	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			31		- ns
Turn-Off Delay Time	t _{d(OFF)}				22		
Fall Time	t _f				13		
Turn-On Delay Time	t _{d(ON)}				10		
Rise Time	t _r	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			23		1
Turn-Off Delay Time	t _{d(OFF)}				30		ns
Fall Time	t _f				10		1

- 5. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
 6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit		
DRAIN-SOURCE DIODE CHARACTERISTICS									
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V,	$T_J = 25^{\circ}C$		0.77	1.0			
		$V_{GS} = 0 \text{ V},$ $I_{S} = 30 \text{ A}$	T _J = 125°C		0.70		V		
Reverse Recovery Time	t _{RR}	V _{GS} = 0 V, dIS/dt = 100 A/μs, I _S = 30 A			27	50			
Charge Time	t _a				15		ns		
Discharge Time	t _b				12				
Reverse Recovery Charge	Q _{RR}				18		nC		
PACKAGE PARASITIC VALUES									
Source Inductance	L _S	T _A = 25°C			0.65		nΗ		
Drain Inductance	L _D				0.005		nΗ		
Gate Inductance	L _G				1.84		nΗ		
Gate Resistance	R_{G}				1.3	5.0	Ω		

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

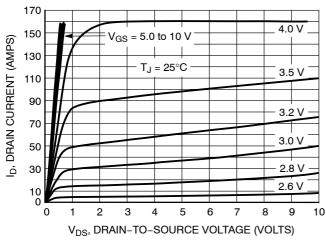


Figure 1. On-Region Characteristics

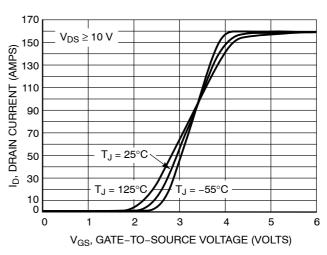


Figure 2. Transfer Characteristics

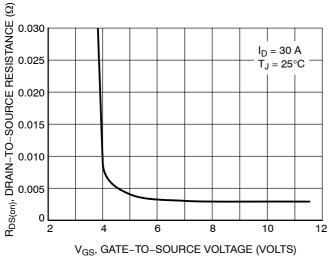


Figure 3. On-Resistance vs. Gate-to-Source Voltage

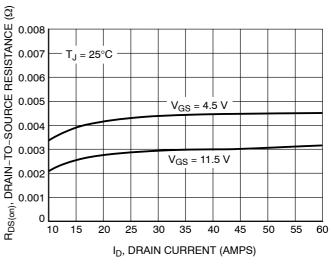


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

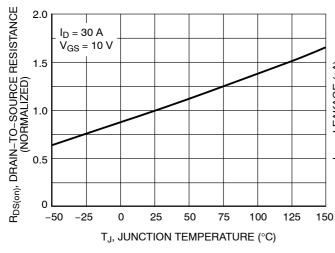


Figure 5. On–Resistance Variation with Temperature

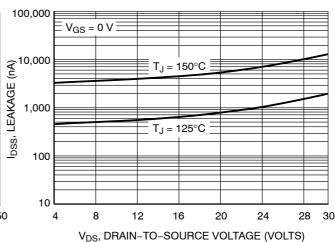
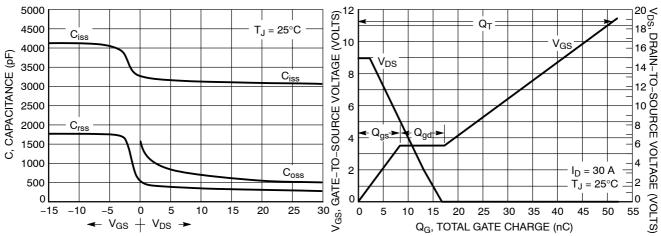


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

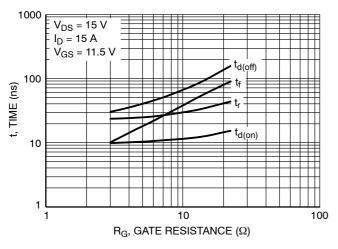


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

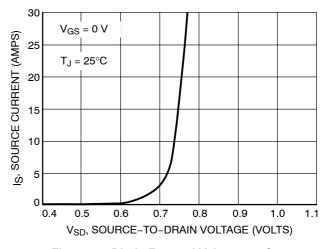


Figure 10. Diode Forward Voltage vs. Current

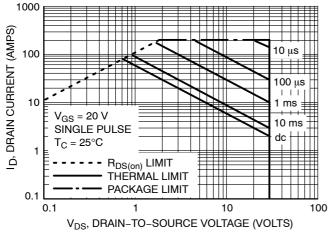


Figure 11. Maximum Rated Forward Biased Safe Operating Area

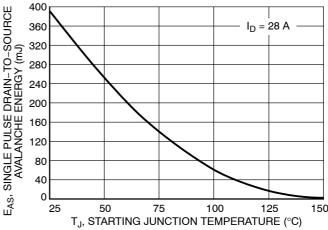


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

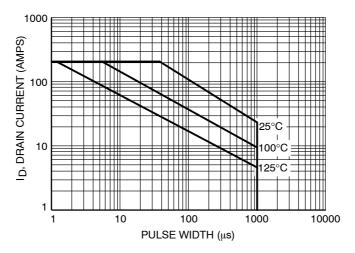
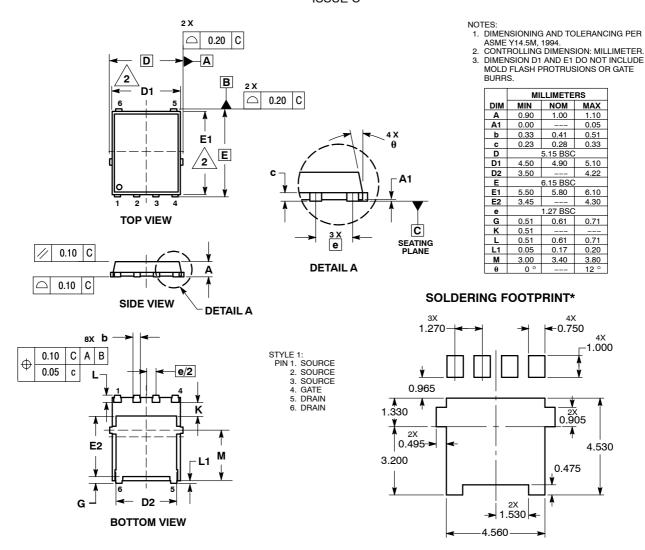


Figure 13. Avalanche Characteristics

PACKAGE DIMENSIONS

DFN6 5x6, 1.27P (SO8 FL)CASE 488AA-01 ISSUE C



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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